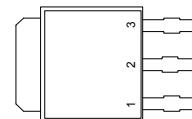
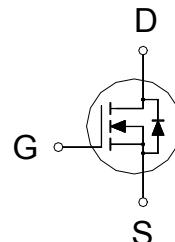


**NIKO-SEM**
**N-Channel Enhancement Mode  
Field Effect Transistor**
**P6006BI**  
TO-251  
Halogen-Free & Lead-Free
**PRODUCT SUMMARY**

$V_{(BR)DSS}$	$R_{DS(ON)}$	$I_D$
60V	65mΩ	18A



1. GATE
- 
2. DRAIN
- 
3. SOURCE

**ABSOLUTE MAXIMUM RATINGS ( $T_A = 25^\circ\text{C}$  Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNITS
Drain-Source Voltage		$V_{DS}$	60	V
Gate-Source Voltage		$V_{GS}$	±20	V
Continuous Drain Current	$T_C = 25^\circ\text{C}$	$I_D$	18	A
	$T_C = 100^\circ\text{C}$		11.8	
Pulsed Drain Current <sup>1</sup>		$I_{DM}$	34	
Avalanche Current		$I_{AS}$	18	
Avalanche Energy	$L = 0.1\text{mH}$	$E_{AS}$	16	mJ
Power Dissipation	$T_C = 25^\circ\text{C}$	$P_D$	50	W
	$T_C = 100^\circ\text{C}$		20	
Junction & Storage Temperature Range		$T_J, T_{stg}$	-55 to 150	°C

**THERMAL RESISTANCE RATINGS**

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Case	$R_{\theta JC}$		2.5	°C / W

<sup>1</sup>Pulse width limited by maximum junction temperature.
**ELECTRICAL CHARACTERISTICS ( $T_J = 25^\circ\text{C}$ , Unless Otherwise Noted)**

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
<b>STATIC</b>						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0\text{V}, I_D = 250\mu\text{A}$	60			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	1	1.6	2.5	
Gate-Body Leakage	$I_{GSS}$	$V_{DS} = 0\text{V}, V_{GS} = \pm 20\text{V}$			±100	nA
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 48\text{V}, V_{GS} = 0\text{V}$			1	
		$V_{DS} = 40\text{V}, V_{GS} = 0\text{V}, T_J = 125^\circ\text{C}$			10	μA
Drain-Source On-State Resistance <sup>1</sup>	$R_{DS(\text{ON})}$	$V_{GS} = 5\text{V}, I_D = 8\text{A}$		63	80	mΩ
		$V_{GS} = 10\text{V}, I_D = 12\text{A}$		53	65	
Forward Transconductance <sup>1</sup>	$g_{fs}$	$V_{DS} = 15\text{V}, I_D = 12\text{A}$		22		S

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DYNAMIC						
Input Capacitance	$C_{iss}$	$V_{GS} = 0V, V_{DS} = 15V, f = 1MHz$		601		pF
Output Capacitance	$C_{oss}$			48		
Reverse Transfer Capacitance	$C_{rss}$			33		
Gate Resistance	$R_g$	$V_{GS} = 0V, V_{DS} = 0V, f = 1MHz$		2.2		$\Omega$
Total Gate Charge <sup>2</sup>	$Q_g$	$V_{DS} = 0.5V_{(BR)DSS}, I_D = 12A$		13		nC
Gate-Source Charge <sup>2</sup>	$Q_{gs}$			7.6		
Gate-Drain Charge <sup>2</sup>	$Q_{gd}$			4.5		
Turn-On Delay Time <sup>2</sup>	$t_{d(on)}$			2.4		
Rise Time <sup>2</sup>	$t_r$			8.3		
Turn-Off Delay Time <sup>2</sup>	$t_{d(off)}$	$V_{DS} = 30V, I_D \approx 12A, V_{GS} = 10V, R_{GEN} = 6\Omega$		37		nS
Fall Time <sup>2</sup>	$t_f$			44		
				53		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ( $T_J = 25^\circ C$ )						
Continuous Current	$I_S$				18	A
Forward Voltage <sup>1</sup>	$V_{SD}$	$I_F = 12A, V_{GS} = 0V$			1.2	V
Reverse Recovery Time	$t_{rr}$	$I_F = 12A, dI_F/dt = 100A/\mu S$		23		nS
Reverse Recovery Charge	$Q_{rr}$			19		nC

<sup>1</sup>Pulse test : Pulse Width  $\leq 300 \mu sec$ , Duty Cycle  $\leq 2\%$ .

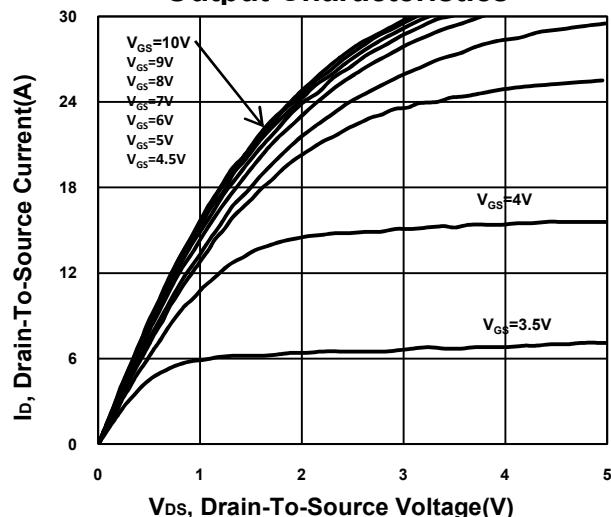
<sup>2</sup>Independent of operating temperature.

**NIKO-SEM**

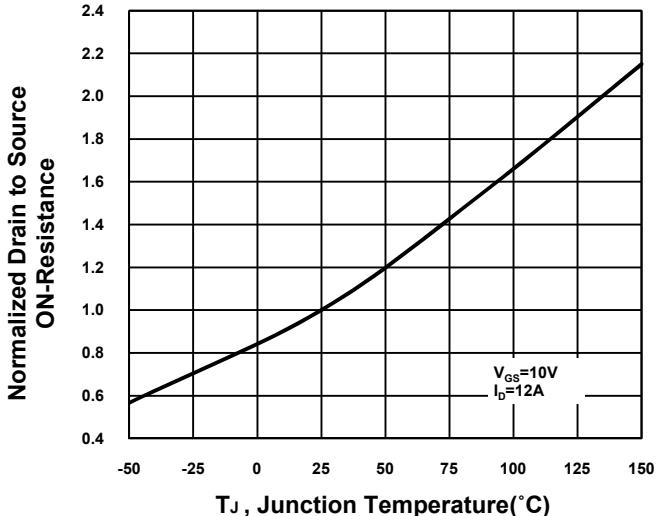
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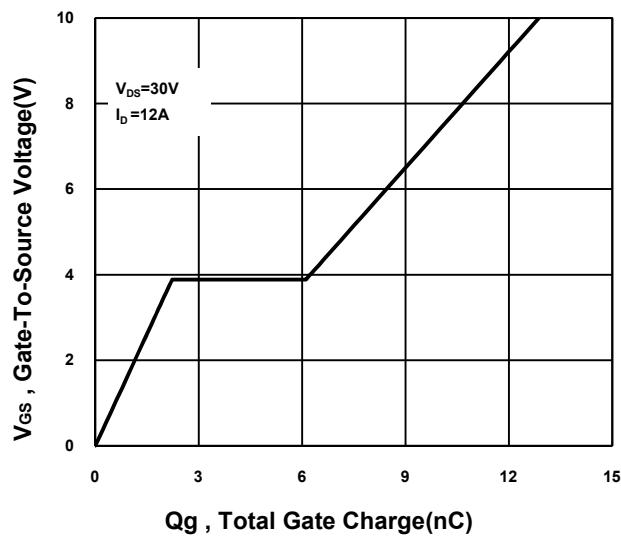
**Output Characteristics**



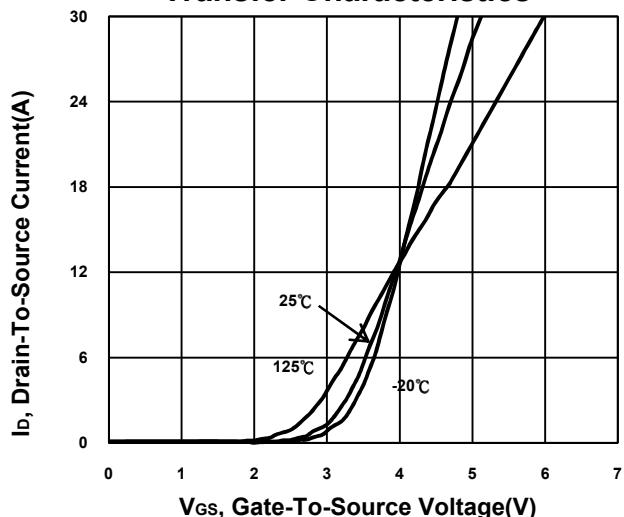
**On-Resistance VS Temperature**



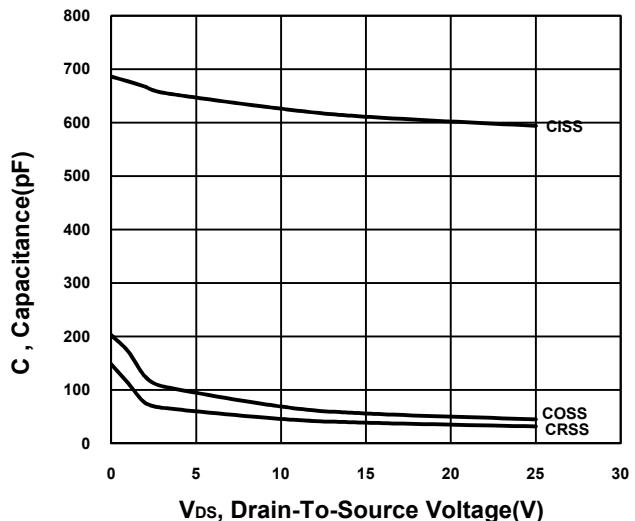
**Gate charge Characteristics**



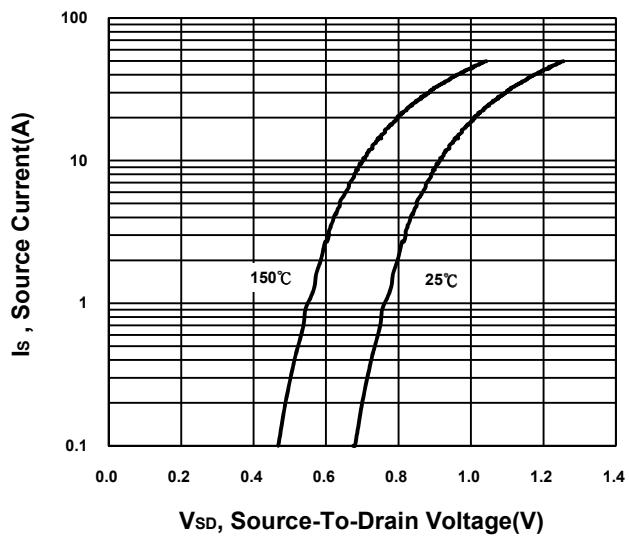
**Transfer Characteristics**



**Capacitance Characteristic**



**Source-Drain Diode Forward Voltage**

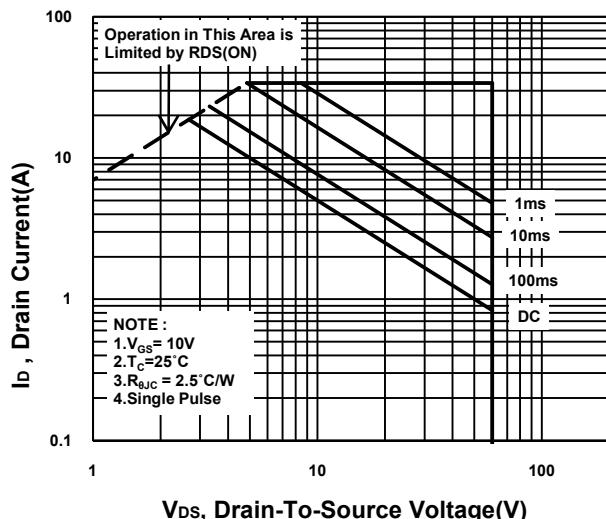


**NIKO-SEM**

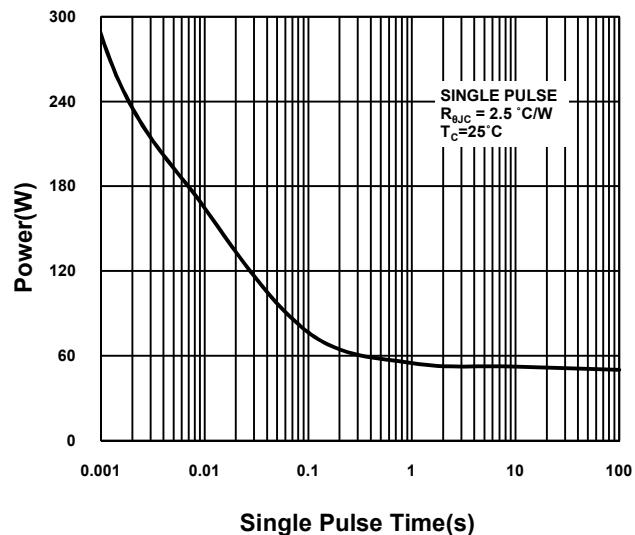
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**Safe Operating Area**



**Single Pulse Maximum Power Dissipation**



**Transient Thermal Response Curve**

